

April 2000

# FQB3P20 / FQI3P20

## 200V P-Channel MOSFET

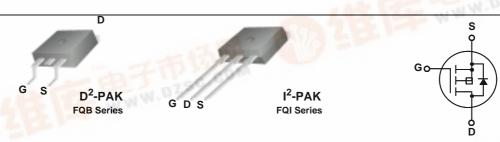
### **General Description**

These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters.

#### **Features**

- -2.8A, -200V,  $R_{DS(on)} = 2.7\Omega$  @ $V_{GS} = -10$  V
- Low gate charge (typical 6.0 nC)
  Low Crss (typical 7.5 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability



# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQB3P20 / FQI3P20	Units	
V <sub>DSS</sub>	Drain-Source Voltage		-200	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C	C)	-2.8	А	
	- Continuous (T <sub>C</sub> = 100	°C)	-1.77	Α	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	-11.2	Α	
V <sub>GSS</sub>	Gate-Source Voltage	AL CONTRACTOR	± 30	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	150	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	-2.8	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	5.2	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-5.5	V/ns	
PD	Power Dissipation (T <sub>A</sub> = 25°C) *		3.13	W	
	Power Dissipation (T <sub>C</sub> = 25°C)		52	W	
	- Derate above 25°C		0.42	W/°C	
$T_J$ , $T_{STG}$	Operating and Storage Temperature Range		-55 to +150	°C	
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

# **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.4	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

<sup>\*</sup> When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-200			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = -250 μA, Referenced to 25°C		-0.18		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -200 V, V <sub>GS</sub> = 0 V			-1	μΑ
		V <sub>DS</sub> = -160 V, T <sub>C</sub> = 125°C			-10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
On Cha	racteristics	,				
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-3.0		-5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -1.4 A		2.06	2.7	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = -40 V, I <sub>D</sub> = -1.4 A (Note 4)		1.23		S
C <sub>oss</sub> C <sub>rss</sub>	Output Capacitance Reverse Transfer Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		45 7.5	60 10	pF pF
C <sub>rss</sub>	' '	1 - 1.0 WHZ		7.5	10	•
Switchi	ing Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = -100 V, I <sub>D</sub> = -2.8 A,		8.5	25	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		35	80	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			12	35	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		25	60	ns
Qg	Total Gate Charge	$V_{DS} = -160 \text{ V}, I_{D} = -2.8 \text{ A},$		6.0	8.0	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = -10 V		1.7		nC
$Q_{gd}$	Gate-Drain Charge	(Note 4, 5)		2.9		nC
Drain-S	Source Diode Characteristics an					
l <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				-2.8	A
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F				-11.2	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -2.8 A			-5.0	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_S = -2.8 \text{ A,}$ $dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)		100		ns μC
$Q_{rr}$	Reverse Recovery Charge			0.34		

- Notes: 
  1. Repetitive Rating : Pulse width limited by maximum junction temperature 
  2. L = 29mH, I<sub>AS</sub> = -2.8A, V<sub>DD</sub> = -50V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> = 25°C 
  3. I<sub>SD</sub>  $\leq$  -2.8A, di/dt  $\leq$  300A/µs, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 
  4. Pulse Test : Pulse width  $\leq$  300µs, Duty cycle  $\leq$  2% 
  5. Essentially independent of operating temperature

# **Typical Characteristics**

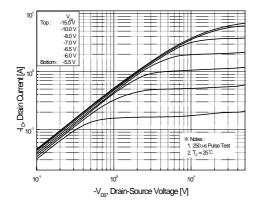


Figure 1. On-Region Characteristics

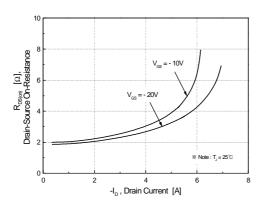


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

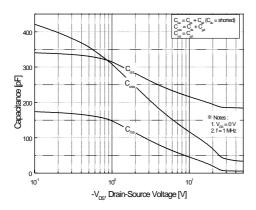


Figure 5. Capacitance Characteristics

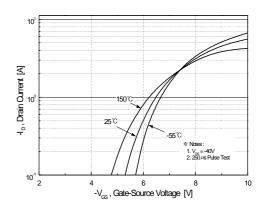


Figure 2. Transfer Characteristics

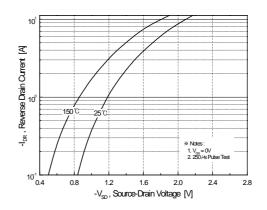


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

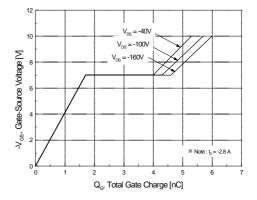


Figure 6. Gate Charge Characteristics

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# Typical Characteristics (Continued)

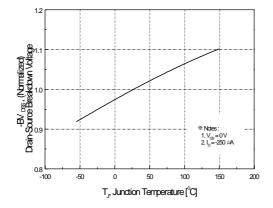


Figure 7. Breakdown Voltage Variation vs. Temperature

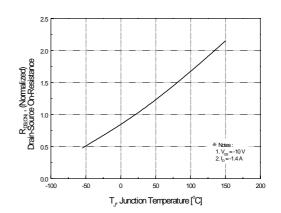


Figure 8. On-Resistance Variation vs. Temperature

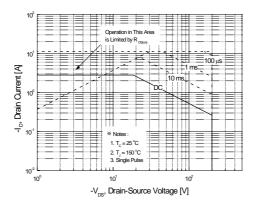


Figure 9. Maximum Safe Operating Area

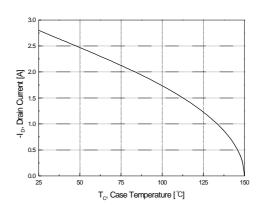


Figure 10. Maximum Drain Current vs. Case Temperature

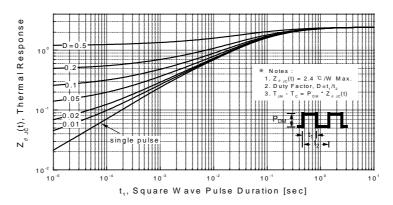
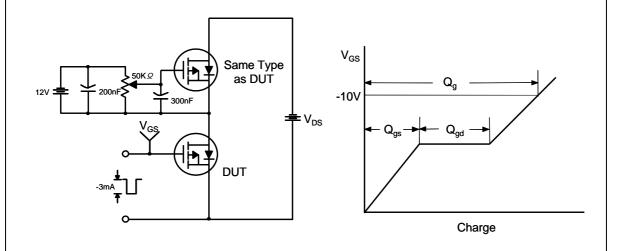


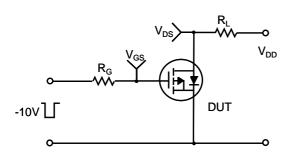
Figure 11. Transient Thermal Response Curve

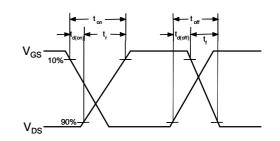
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## **Gate Charge Test Circuit & Waveform**

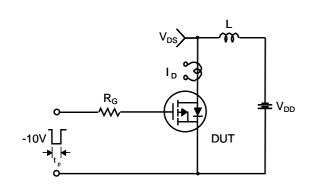


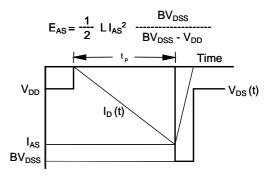
## **Resistive Switching Test Circuit & Waveforms**



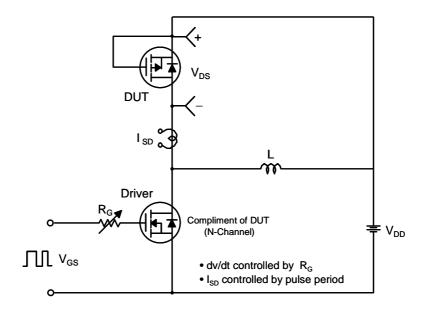


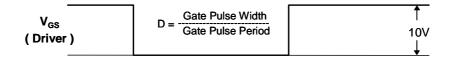
## **Unclamped Inductive Switching Test Circuit & Waveforms**



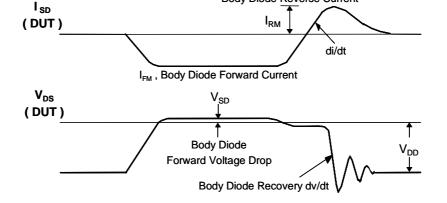


## Peak Diode Recovery dv/dt Test Circuit & Waveforms

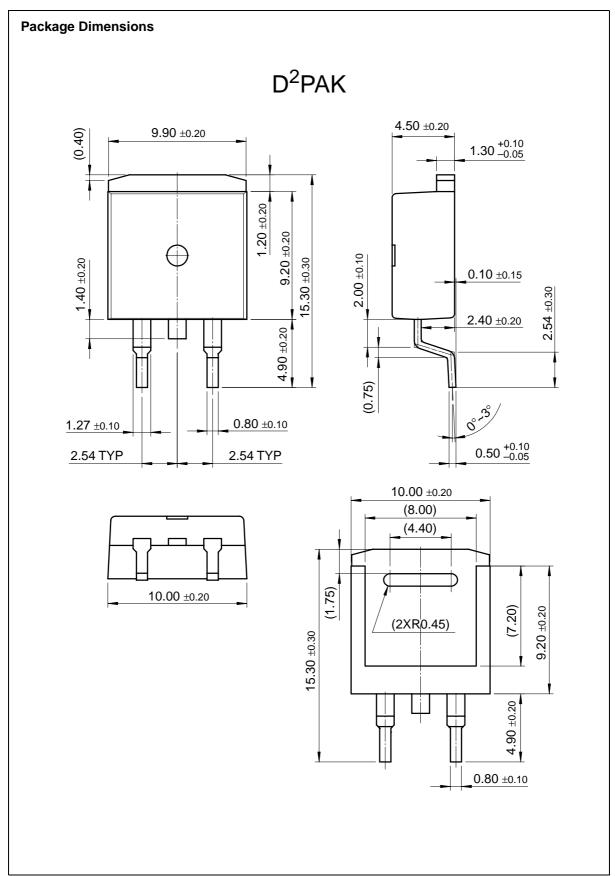


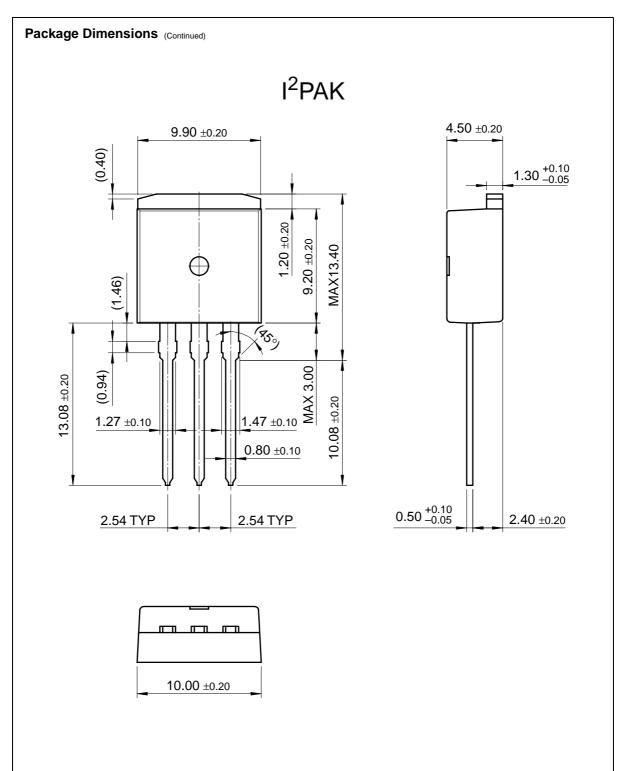


**Body Diode Reverse Current** 



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